SPECIFICATION

SPEC. No. C-Array-a D A T E : 2013 Sep.

То

Non-Controlled Copy

CUSTOMER'S PRODUCT NAME	TDK PRODUCT NAME
	MULTILAYER CERAMIC CHIP CAPACITORS
	CKC Series / Commercial Grade
	2 in 1 Array
	4 in 1 Array
Please return this specification to TDK represent	ntatives.

If orders are placed without returned specification, please allow us to judge that specification is accepted by your side.

RECEIPT CONFIRMATION

DATE:	YEAR	MONTH	DAY

TDK Corporation Sales Electronic Components Sales & Marketing Group TDK-EPC Corporation Engineering Ceramic Capacitors Business Group

APPROVED	Person in charge	APPROVED	CHECKED	Person in charge

1. SCOPE

This specification is applicable to chip type multilayer ceramic capacitors with a priority over the other relevant specifications.

Production places defined in this specification shall be TDK-EPC Corporation Japan,

TDK (Suzhou) Co., Ltd and TDK Components U.S.A. Inc.

EXPLANATORY NOTE:

This specification warrants the quality of the ceramic chip capacitors. The chips should be evaluated or confirmed a state of mounted on your product.

If the use of the chips goes beyond the bounds of the specification, we can not afford to guarantee.

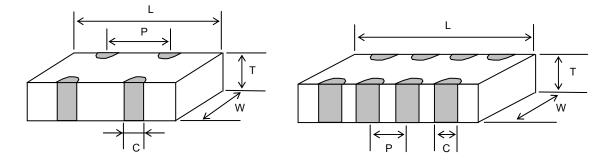
2. CODE CONSTRUCTION

(Example)								
Catalog Number :	<u>CKCL22</u>	<u>X5R</u>	<u>0J</u>	<u>105</u>	M	<u>085</u>	<u>A</u>	<u>A</u>
(Web)	<u>CKCA43</u>	<u>X7R</u>	<u>1H</u>	<u>102</u>	M	<u>100</u>	<u>A</u>	<u>A</u>
	(1)	(2)	(3)	(4)	(5)	(6)	(7)	(8)
Item Description :	CKCL22	<u>X5R</u>	<u>0J</u>	<u>105</u>	M	<u>T</u>	<u>XXXX</u>	
	<u>CKCA43</u>	<u>X7R</u>	<u>1H</u>	<u>102</u>	M	<u>T</u>	XXXX	
	(1)	(2)	(3)	(4)	(5)	(9)	(10)	

(1) Type

(2 element)

(4 element)



Please refer to product list for the dimension of each product.

(2) Temperature Characteristics (Details are shown in table 1 No.7 at page4 and No.8 at page 5)

(3) Rated Voltage

Symbol	Rated Voltage
1 H	DC 50 V
1 E	DC 25 V
1 C	DC 16 V
1 A	DC 10 V
0 J	DC 6.3 V



— 1 –

(4) Rated Capacitance

Stated in three digits and in units of pico farads (pF).

The first and Second digits identify the first and second significant figures of the capacitance, the third digit identifies the multiplier.

R is designated for a decimal point.

(5) Capacitance tolerance

Symbol	Tolerance	Capacitance
F	± 1 pF	10pF
К	± 10 %	Over 10pF
М	± 20 %	Over TopP

(6) Thickness code (Only Catalog Number)

(7) Package code (Only Catalog Number)

- (8) Special code (Only Catalog Number)
- (9) Packaging (Only Item Description)

)		
,	Symbol	Packaging
	В	Bulk
	Т	Taping

(10) Internal code (Only Item Description)



3. RATED CAPACITANCE AND CAPACITANCE TOLERANCE

3.1 Standard combination of rated capacitance and tolerances

Class	Temperature Characteristics	Capacitance tolerance	Rated capacitance
1	1 C H COG	F (± 1pF)	10pF
1		K (± 10 %)	E – 6 series
2	J B X5R X7R X8R	M (± 20 %)	E – 3 series

3.2 Capacitance Step in E series

E series	Capacitance Step					
E- 3	1	.0	2	.2	4	.7
E- 6	1.0	1.5	2.2	3.3	4.7	6.8

4. OPERATING TEMPERATURE RANGE

T.C.	Min. operating Temperature	Max. operating Temperature	Reference Temperature
C H J B	-25°C	85°C	20°C
X5R	-55°C	85°C	25°C
X7R C0G	-55°C	125°C	25°C
X8R	-55°C	150°C	25°C

5. STORING CONDITION AND TERM

5 to 40°C at 20 to 70%RH 6 months Max.

6. INDUSTRIAL WASTE DISPOSAL

Dispose this product as industrial waste in accordance with the Industrial Waste Law.



7. PERFORMANCE

table 1

No.	Item	Perfor		or inspection		
1	External Appearance	No defects which n performance.	Inspect with	magnifying g	glass (3×)	
2	Insulation Resistance	10,000MΩ min. (As for the capacito 16, 10, 6.3V DC, 10 whichever smaller.		between eac voltage for 60		
3	Voltage Proof	Withstand test volta insulation breakdov damage.		3 × rated 2.5 × rate oltage shall b	• •	
				terminal for charge curre A.		
4	Capacitance	ce Within the specified tolerance.		Class	Measuring frequency	Measuring voltage
					1MHz±10%	0.5-5 Vrms.
				Class2 To measure	1kHz±10% between eac	1.0±0.2Vms.
5	Q (Class1)	30pF and over Under 30pF	ication Q ≥ 1,000 Q ≥ 400+20·C	See No.4 in condition.	this table for	measuring
6	Dissipation Factor	C : Rated capacita	nce (pF)	See No 4 in	this table for	measuring
0	(Class2)	T.C. J B X5R X7R X7R X8R	D.F. 0.025 max. 0.03 max. 0.05 max.	condition.		measuring
7	Temperature Characteristics of Capacitance (Class1)	T.C.Temperature CoefficientC H $0 \pm 60 \text{ (ppm/°C)}$ C0G $0 \pm 30 \text{ (ppm/°C)}$ Capacitance drift within $\pm 0.2\%$ or $\pm 0.05 \text{pF}$, whichever larger.		calculated b and 85°C te Measuring te	e coefficient s ased on valu mperature. emperature b °C and -25°C	es at 25°C pelow 20°C



No.	Item	Performance	Test or inspection method
8	Temperature Characteristics of Capacitance (Class2)	Capacitance Change (%) No voltage applied J B : ± 10 X5R : ± 15 X7R : ± 15 X8R : ± 15	Capacitance shall be measured by the steps shown in the following table after thermal equilibrium is obtained for each step. ΔC be calculated ref. STEP3 reading $\underline{\Delta C}$ be calculated ref. STEP3 reading \underline{Step} Temperature(°C)1Reference temp. ± 2 2Min. operating temp. ± 3 3Reference temp. ± 2 4Max. operating temp. ± 2
9	Robustness of Terminations	No sign of termination coming off, breakage of ceramic, or other abnormal signs.	Reflow solder the capacitors on a P.C.Board shown in Appendix1 to 3 and apply a pushing force of 5N with 10±1s. $\boxed{\bigcirc \bigcirc \bigcirc \bigcirc \bigcirc \bigcirc 5N}_{Capacitor} \ \ \ \ \ \ \ \ \ \ \ \ \ $
10	Solderability	New solder to cover over 75% of termination. 25% may have pin holes or rough spots but not concentrated in one spot. Ceramic surface of A sections shall not be exposed due to melting or shifting of termination material.	Completely soak both terminations in solder at 235±5°C for 2±0.5s. Solder : H63A (JIS Z 3282) Flux: Isopropyl alcohol (JIS K 8839) Rosin (JIS K 5902) 25% solid solution.



No.	lte	em		Perfo	ormance		Test or inspection m	nethod	
11	Vibration External appearance		No mechanical damage.			Reflow solder the capacitors on a P.C.Board shown in Appendix 1 to 3			
		Capacitance	Characteristics Change from the value before test				before testing.		
			Class1	C H C0G	±2.5% or ±0.25pF, whichever larger.	1.5mn	e the capacitors with n P-P changing the fr 0Hz to 55Hz and bac	equencies	
			Class2	J B X5R X7R X8R	± 7.5 %	about Repea	from 10Hz to 55Hz and back to 10H about 1min. Repeat this for 2h each in 3 perpendicular directions.		
						_			
		Q (Class1)	Rat Capac		Q				
			30pF ar	nd over	1,000 min.				
			Under 3	80pF	400+20×C min.				
			C : Rated capacitance (pF)						
	D.F. (Class2)		Meet the initial spec.						
12	Temperature cycle	External appearance	No mechanical damage.			Reflow solder the capacitors on a P.C.Board shown in Appendix 1 to 3 before testing.			
		Capacitance	Characteristics Change from the						
			Charact	eristics	value before test	Expose the capacitors in the con		e condition	
			Class1	C H C0G	±2.5% or ±0.25pF, whichever larger.	-	step1 through step 4 and repeat 5 tir consecutively.		
			Class2	J B X5R X7R X8R	± 7.5 %	Leave the capacitors in ambient condition for 6 to 24h (Class 1) or 24 ± 2h (Class 2) before measurement.			
		Q							
		(Class1)	Rat Capac		Q	Step	Temperature(°C) Min. operating temp.	Time (min.)	
			30pF ar	nd over	1,000 min.	1	per para.4. ± 3	30 ± 3	
			Under 3	80pF	400+20×C min.	2	Reference temp. per para.4.	2 - 5	
			C : F	Rated ca	apacitance (pF)	3	Max. operating	30 ± 2	
		D.F. (Class2)	Meet the	initial s	pec.	4	temp. per para.4. ± 2 Reference temp. per para.4.	2 - 5	
		Insulation Resistance	Meet the	initial s	pec.	1		1	
		Voltage proof	No insula damage.	tion bre	eakdown or other	1			



No.	lte	em		Perfo	rmance	Test or inspection method
13	Moisture Resistance	External appearance	No mecha	nical da	amage.	Reflow solder the capacitors on a P.C.Board shown in Appendix 1 to 3
	(Steady State)	Capacitance	Charact	eristics	Change from the value before test	before testing.
			Class1	C H C0G	±5% or ±0.5pF, whichever larger.	Leave at temperature $40 \pm 2^{\circ}$ C, 90 to 95%RH for 500 +24,0h.
			Class2	J B X5R X7R X8R	± 10 % ± 12.5 %	Leave the capacitors in ambient condition for 6 to 24h (Class1) or 24 : 2h (Class2) before measurement.
		Q (Class1)		ited citance	Q	
			30pF ar	nd over	350 min.	
			10pF ar to unde		275+5/2×C min.	
			Unde	r 10pF	200+10×C min.	
			C : Rated capacitance (pF)			
		D. F. (Class2)	200% of initial spec. max.			
		Insulation Resistance	1,000M Ω min. (As for the capacitors of rated voltage 16, 10, 6.3V DC, 10M Ω ·µF min.,)			
14	Moisture Resistance	External appearance	No mechanical damage.			Reflow solder the capacitors on a P.C.Board shown in Appendix 1 to 3
		Capacitance	Charact	Characteristics Change from the value before test		before testing. Apply the rated voltage at
			Class1	C H C0G	±7.5% or ±0.75pF, whichever larger.	temperature $40 \pm 2^{\circ}$ C and 90 to 95%RH for 500 +24,0h.
			Class2	J B X5R X7R X8R	± 10 % ± 12.5 %	Charge/discharge current shall not exceed 50mA.
		0				Leave the capacitors in ambient condition for 6 to 24h (Class1) or 24 :
		Q (Class1)	Rate Capaci		Q	2h (Class2) before measurement.
			30pF and	lover	200 min.	Voltage conditioning (only for class 2 Voltage treat the capacitors under
			Under	30pF	100+10/3×C min.	testing temperature and voltage for 1
			C : Rated capacitance (pF)			hour. Leave the capacitors in ambient
		D. F. (Class2)	200% of ir	nitial sp	ec. max.	condition for 24±2h before measurement.
		Insulation Resistance		e capac	itors of rated 3V DC, 5MΩ·μF	Use this measurement for initial value.

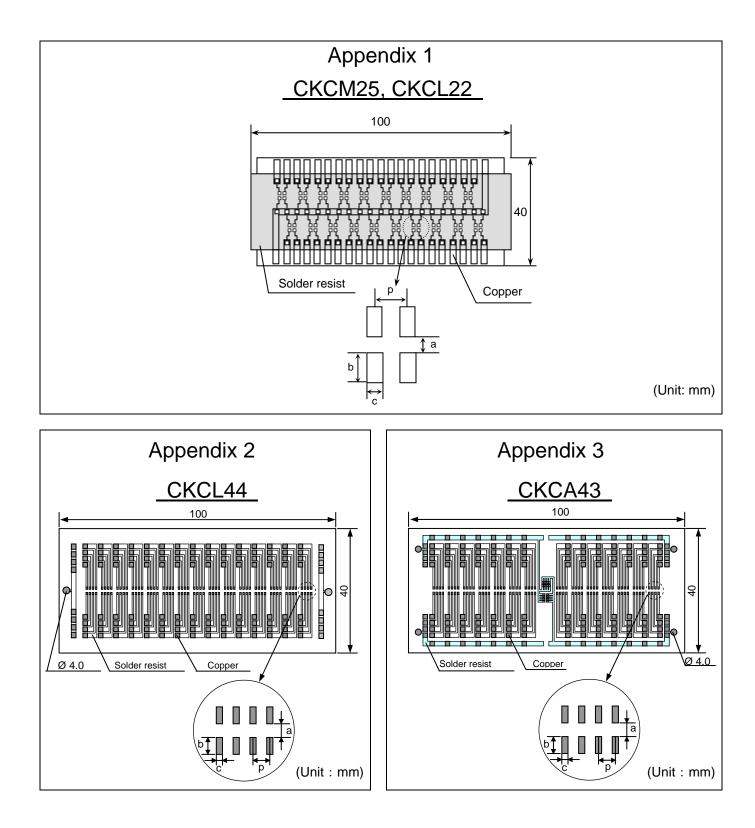




No.	ľ	tem	Performance		rmance	Test or inspection method
15	Life	External appearance	No mechanical damage.			Reflow solder the capacitors on a P.C.Board shown in Appendix 1 to 3
		Capacitance	Charact	eristics C H	Change from the value before test ±3% or ±0.3pF,	 before testing. Below the voltage shall be applied at maximum operating temperature ± 2°C
			Class1	C0G J B	whichever larger.	for 1,000 +48, 0h. Applied voltage
			Class2	X5R X7R X8R	± 12.5 % ± 15 %	Rated voltage × 2 Rated voltage × 1.5
	Q (Class1)	Q		ated		Rated voltage × 1
		(Class1)		tance	Q	For information which product has
			30pF a 10pF a	nd over	350 min.	which applied voltage, please contact with our sales representative.
			to under		275+5/2×C min.	Charge/discharge current shall not exceed 50mA.
			Unde	r 10pF	200+10×C min.	Leave the capacitors in ambient
			C : Rateo	d capaci	itance (pF)	condition for 6 to 24h (Class1) or 24±2h (Class2) before measurement.
		D. F. (Class2)	200% of initial spec. max.			Voltage conditioning (only for class 2) Voltage treat the capacitors under
		Insulation Resistance	•	e capao	citors of rated 6.3V DC, 10MΩ·µF	 testing temperature and voltage for 1 hour. Leave the capacitors in ambient condition for 24±2h before measurement. Use this measurement for initial value.

*As for the initial measurement of capacitors (Class2) on number 8,11,12 and 13, leave capacitors at 150 $-10,0^{\circ}$ C for 1 hour and measure the value after leaving capacitors for 24 ± 2h in ambient condition.





Material : Glass Epoxy (As per JIS C6484 GE4)

P.C. Board thickness : 1.6mm

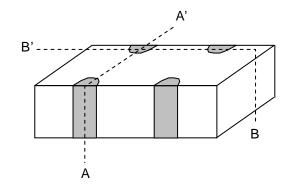


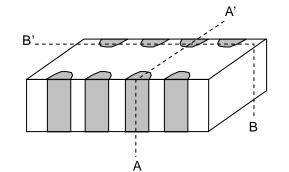
Copper (thickness 0.035mm) Solder resist

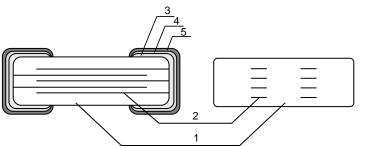
	Dimensions (mm)						
TDK (EIA style)	а	b	С	р			
CKCM25	0.5	0.5	0.36	0.64			
CKCL22	0.6	0.6	0.45	1.0			
CKCL44	0.6	0.7	0.2	0.5			
CKCA43	1.0	0.7	0.3	0.8			

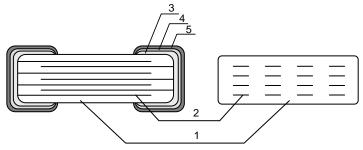


8. INSIDE STRUCTURE AND MATERIAL



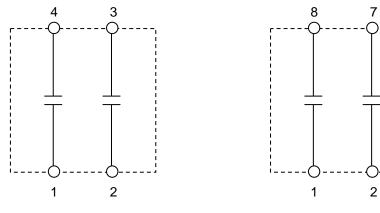


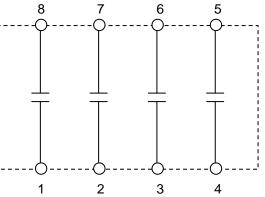




No.	NAME	MATERIAL			
NO.	NAME	Class1	Class2		
1	Dielectric	CaZrO ₃	BaTiO ₃		
2	Electrode	Nickel (Ni)			
3		Copper (Cu)			
4	Termination	Nickel (Ni)			
5		Tin (Sn)			

9. EQUIVALENT CIRCUIT







10. Caution

	Caution	
No.	Process	Condition
1	Operating Condition (Storage,	 1-1. Storage 1) The capacitors must be stored in an ambient temperature of 5 to 40°C with a relative humidity of 20 to 70%RH. The products should be used within 6 months upon receipt.
	Transportation)	2) The capacitors must be operated and stored in an environment free of dew condensation and these gases such as Hydrogen Sulphide, Hydrogen Sulphate, Chlorine, Ammonia and sulfur.
		3) Avoid storing in sun light and falling of dew.
		4) Do not use capacitors under high humidity and high and low atmospheric pressure which may affect capacitors reliability.
		5) Capacitors should be tested for the solderability when they are stored for long time.
		1-2. Handling in transportation
		In case of the transportation of the capacitors, the performance of the capacitors may be deteriorated depending on the transportation condition. (Refer to JEITA RCR-2335B 9.2 Handling in transportation)
2	Circuit design	 2-1. Operating temperature Operating temperature should be followed strictly within this specification, especially be careful with maximum temperature. 1) Do not use capacitors above the maximum allowable operating temperature.
		2) Surface temperature including self heating should be below maximum operating
		 2) Surface temperature including sen heating should be below maximum operating temperature. (Due to dielectric loss, capacitors will heat itself when AC is applied. Especially at high frequencies around its SRF, the heat might be so extreme that it may damage itself or the product mounted on. Please design the circuit so that the maximum temperature of the capacitors including the self heating to be below the maximum allowable operating temperature. Temperature rise at capacitor surface shall be below 20°C)
		 3) The electrical characteristics of the capacitors will vary depending on the temperature. The capacitors should be selected and designed in taking the temperature into consideration. 2-2. Operating voltage 1) Operating voltage across the terminals should be below the rated voltage. When AC and DC are super imposed, V_{0-P} must be below the rated voltage.
		AC or pulse with overshooting, $V_{P,P}$ must be below the rated voltage. (1) and (2)
		(3), (4) and (5) When the voltage is started to apply to the circuit or it is stopped applying, the irregular voltage may be generated for a transit period because of resonance or switching. Be sure to use the capacitors within rated voltage containing these Irregular voltage.
		Voltage (1) DC voltage (2) DC+AC voltage (3) AC voltage
		Positional Measurement (Rated voltage) v_{0-P} v_{0-
		Voltage (4) Pulse voltage (A) (5) Pulse voltage (B)
		Positional Measurement (Rated voltage) V_{P-P} V_{P-P} V_{P-P}





No.	Process			Condition				
2	Circuit design 2) Even below the rated voltage, if repetitive high frequency AC or pulse the reliability of the capacitors may be reduced.							
		The capacitors	 The effective capacitance will vary depending on applied DC and AC voltages. The capacitors should be selected and designed in taking the voltages into consideration. 					
			pacitors (Class 2) ay vibrate themse		and/or pulse voltaç te audible sound.	ges, the		
3[Designing P.C.board	 The amount of solder at the terminations has a direct effect on the reliability of the capacitors. 1) The greater the amount of solder, the higher the stress on the chip capacitors, and the more likely that it will break. When designing a P.C.board, determine the shape and size of the solder lands to have proper amount of solder on the terminations. 						
		 Avoid using common solder land for multiple terminations and provide individual solder land for each terminations. 						
		3) Size and record	mmended land di	mensions.				
			$\begin{array}{c} \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\ \\$			↓A ↓B		
						(mm)		
		Type Symbol	CKCM25	CKCL22	CKCL44	CKCA43		
		P	0.64	1.0	0.5	0.8		
		A	0.3	0.4	0.55	0.6 - 0.7		
		B	0.45	0.6	0.6	0.8 - 1.0		
		С	0.3	0.5	0.25	0.4		



No.	Process	Condition					
3	Designing P.C.board	4) Recor	4) Recommended chip capacitors layout is as following.				
				Disadvantage against bending stress	Advantage against bending stress		
				Perforation or slit	Perforation or slit		
			ounting face		(Little Barrier Barri		
				Break P.C.board with mounted side up.	Break P.C.board with mounted side down.		
				Mount perpendicularly to perforation or slit	Mount in parallel with perforation or slit		
				Perforation or slit	Perforation or slit		
			Chip arrangement (Direction)				
				Closer to slit is higher stress	Away from slit is less stress		
			nce from slit	$(\ell_1 < \ell_2)$	l_2 $(l_1 < l_2)$		



No.	Process	Condition
3	Designing P.C.board	5) Mechanical stress varies according to location of chip capacitors on the P.C.board.
		Perforation
		The stress in capacitors is in the following order. A > B = C > D > E
4	Mounting	 4-1. Stress from mounting head If the mounting head is adjusted too low, it may induce excessive stress in the chip capacitors to result in cracking. Please take following precautions. 1) Adjust the bottom dead center of the mounting head to reach on the P.C.board surface and not press it. 2) Adjust the mounting head pressure to be 1 to 3N of static weight. 3) To minimize the impact energy from mounting head, it is important to provide support from the bottom side of the P.C.board. See following examples.
		Not recommended Recommended
		Single sided mounting Support
		Double-sides mounting Solder 1 peeling Crack
		When the centering jaw is worn out, it may give mechanical impact on the capacitors to cause crack. Please control the close up dimension of the centering jaw and provide sufficient preventive maintenance and replacement of it.



No.	Process		Cond	ition			
5	Soldering	activity may also degrade the	5-1. Flux selection Although highly-activated flux gives better solderability, substances which increase activity may also degrade the insulation of the chip capacitors. To avoid such degradation, it is recommended following.				
		 It is recommended to use Strong flux is not recomm 	e a mildly active ended.	ated rosin flux (less than 0.1wt% chlorine			
				provide proper amount of flux.			
		3) When water-soluble flux is	s used, enough	washing is necessary.			
		5-2. Recommended soldering	g profile by vario	ous methods			
			Reflow so	-			
		←	Preheating	Soldering →			
		Book					
		Peak Temp	1				
		(C)	ΔΤ				
		Temp. (°C)					
		0		<u>```</u>			
		←	Over 60 sec.	←→ Peak Temp time			
		Manual soldering					
			(Solde	er iron)			
		300		—, ,			
		Ĵ.	ΔΤ				
		à					
		Le Le					
			Preheating				
		0		3sec. (As short as possible)			
		5-3. Recommended soldering	n peak temp an	d peak temp duration			
		Temp./Duration	Reflow s	<u> </u>			
		Solder	Peak temp(°C)	Duration(sec.)			
		Sn-Pb Solder	230 max.	20 max.			
		Lead Free Solder	260 max.	10 max.			
		Recommended solder co Sn-37Pb (Sn-Pb solder)					
		Sn-3.0Ag-0.5Cu (Lead F					



No.	Process	Condition						
5	Soldering	5-4. Avoiding thermal shock						
		1) Preheating condition						
		Soldoring		Temp. (°C)				
		Soldering	CKCM25, CKC	L22, CKCL44	CKCA43			
		Reflow soldering	$\Delta T \leq T$	150	∆T ≤ 130			
		Manual soldering	$\Delta T \leq T$	150	∆T ≤ 130			
		 Cooling condition Natural cooling using a cleaning, the temperature 			••			
		5-5. Amount of solder Excessive solder wil temperature change detach the capacitor	s and it may resu	It in chip cracking	capacitors when . In sufficient solder ma			
		Excessive	A A A A A A A A A A A A A A A A A A A		her tensile force in p capacitors to cause ck			
		Adequate	A A A A A A A A A A A A A A A A A A A	Maximum amo				
		Insufficient solder		cau chi	w robustness may use contact failure or p capacitors come off P.C.board.			
		5-6. Solder repair by solder	iron					
		 Selection of the solderin Tip temperature of sold land size. The higher the heat shock may cause Please make sure the time in accordance with chip capacitors with the 	der iron varies by he tip temperature a crack in the ch tip temp. before s h following recom	e, the quicker the ip capacitors. soldering and kee mended condition	operation. However, p the peak temp and n. (Please preheat the			
		Recommended solder iron condition (Sn-Pb Solder and Lead Free Solder)						
		Temp. (°C)	Duration (sec.)	Wattage (W)	Shape (mm)			
		300 max.	3 max.	20 max.	Ø 3.0 max.			
		 Direct contact of the so cause crack. Do not tou iron. 	•					



No.	Process	Condition
5	Soldering	 5-7. Sn-Zn solder Sn-Zn solder affects product reliability. Please contact TDK in advance when utilize Sn-Zn solder. 5-8. Countermeasure for tombstone The misalignment between the mounted positions of the capacitors and the land patterns should be minimized. The tombstone phenomenon may occur especially the capacitors are mounted (in longitudinal direction) in the same direction of the reflow soldering. (Refer to JEITA RCR-2335B Annex 1 (Informative) Recommendations to prevent the tombstone phenomenon)
6	Cleaning	 If an unsuitable cleaning fluid is used, flux residue or some foreign articles may stick to chip capacitors surface to deteriorate especially the insulation resistance. If cleaning condition is not suitable, it may damage the chip capacitors.
		2)-1. Insufficient washing
		 Terminal electrodes may corrode by Halogen in the flux. Halogen in the flux may adhere on the surface of capacitors, and lower the insulation resistance. Water soluble flux has higher tendency to have above mentioned problems (1) and (2).
		2)-2. Excessive washing
		When ultrasonic cleaning is used, excessively high ultrasonic energy output can affect the connection between the ceramic chip capacitor's body and the terminal electrode. To avoid this, following is the recommended condition.
		Power: 20 W/ ℓ max. Frequency: 40 kHz max. Washing time: 5 minutes max.
		2)-3. If the cleaning fluid is contaminated, density of Halogen increases, and it may bring the same result as insufficient cleaning.
7	Coating and molding of the P.C.board	 When the P.C.board is coated, please verify the quality influence on the product. Please verify carefully that there is no harmful decomposing or reaction gas emission during curing which may damage the chip capacitors. Please verify the curing temperature.



No.	Process	Condition							
8	Handling after chip mounted	1)Please pay attention not to bend or distort the P.C.board after soldering in handling otherwise the chip capacitors may crack.							
			Bend	Twist					
		2) When functional check of the P.C.board is performed, check pin pressure tends to be adjusted higher for fear of loose contact. But if the pressure is excessive and bend the P.C.board, it may crack the chip capacitors or peel the terminations off. Please adjust the check pins not to bend the P.C.board.							
		Item	Not recommended	Recommended					
		Board bending	Termination peeling Check pin	Support pin					
9	Handling of loose chip capacitors	 1) If dropped the chip capacitors may crack. Once dropped do not use it. Esperthe large case sized chip capacitors are tendency to have cracks easily, so phandle with care. Floor 2) Piling the P.C.board after mounting for storage or handling, the corner of the P.C.board may hit the chip capacitors of another board to cause crack. 							



No.	Process	Condition
10	Capacitance aging	The capacitors (Class 2) have aging in the capacitance. They may not be used in precision time constant circuit. In case of the time constant circuit, the evaluation should be done well.
11	Estimated life and estimated failure rate of capacitors	As per the estimated life and the estimated failure rate depend on the temperature and the voltage. This can be calculated by the equation described in JEITA RCR-2335B Annex 6 (Informative) Calculation of the estimated lifetime and the estimated failure rate (Voltage acceleration coefficient : 3 multiplication rule, Temperature acceleration coefficient : 10°C rule) The failure rate can be decreased by reducing the temperature and the voltage but they will not be guaranteed.
12	Others	The products listed on this specification sheet are intended for use in general electronic equipment (AV equipment, telecommunications equipment, home appliances, amusement equipment, computer equipment, personal equipment, office equipment, measurement equipment, industrial robots) under a normal operation and use condition.
		The products are not designed or warranted to meet the requirements of the applications listed below, whose performance and/or quality require a more stringent level of safety or reliability, or whose failure, malfunction or trouble could cause serious damage to society, person or property. Please understand that we are not responsible for any damage or liability caused by use of the products in any of the applications below or for any other use exceeding the range or conditions set forth in this specification sheet. If you intend to use the products in the applications listed below or if you have special requirements exceeding the range or conditions set forth in this specification, please contact us.
		 (1) Aerospace/Aviation equipment (2) Transportation equipment (cars, electric trains, ships, etc.) (3) Medical equipment (4) Power-generation control equipment (5) Atomic energy-related equipment (6) Seabed equipment (7) Transportation control equipment (8) Public information-processing equipment (9) Military equipment (10) Electric heating apparatus, burning equipment (11) Disaster prevention/crime prevention equipment (12) Safety equipment (13) Other applications that are not considered general-purpose applications, you are kindly requested to take into consideration securing protection circuit/device or providing backup circuits in your equipment.



11. Packaging label

Packaging shall be done to protect the components from the damage during transportation and storing, and a label which has the following information shall be attached.

1) Inspection No.
 2) TDK P/N
 3) Customer's P/N
 4) Quantity

*Composition of Inspection No.

Example $\underline{M} \underline{2} \underline{A} - \underline{OO} - \underline{OOO}$ (a) (b) (c) (d) (e)

a) Line code

b) Last digit of the year

c) Month and A for January and B for February and so on. (Skip I)

d) Inspection Date of the month.

e) Serial No. of the day

12. Bulk packaging quantity

Total number of components in a plastic bag for bulk packaging: 1,000pcs.



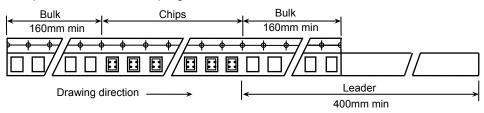
13. TAPE PACKAGING SPECIFICATION

1. CONSTRUCTION AND DIMENSION OF TAPING

1-1. Dimensions of carrier tape

Dimensions of paper tape shall be according to Appendix 4. Dimensions of plastic tape shall be according to Appendix 5.

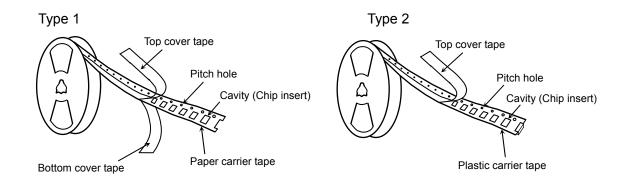
1-2. Bulk part and leader of taping



1-3. Dimensions of reel

Dimensions of Ø178 reel shall be according to Appendix 6. Dimensions of Ø330 reel shall be according to Appendix 7.

1-4. Structure of taping



2. CHIP QUANTITY

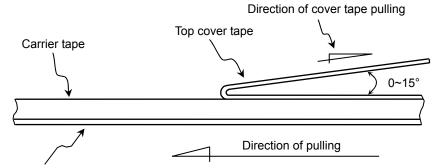
Tupo	Taping	Chip quantity (pcs.)			
Туре	Material	φ178mm reel	φ330mm reel		
CKCM25	Paper		10,000		
CKCL22	Plastic	4,000			
CKCL44	Paper				
CKCA43	Plastic	2,000			





3. PERFORMANCE SPECIFICATIONS

- 3-1. Fixing peeling strength (top tape)
 - 0.05-0.7N. (See the following figure.)



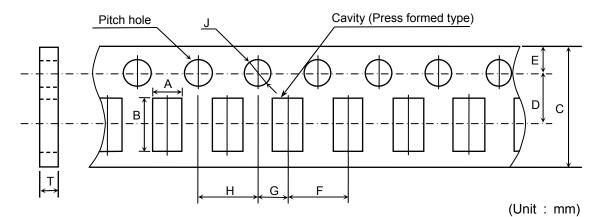
Bottom cover tape (Paper carrier tape of type 1)

- 3-2. Carrier tape shall be flexible enough to be wound around a minimum radius of 30mm with components in tape.
- 3-3. The missing of components shall be less than 0.1%
- 3-4. Components shall not stick to fixing tape.
- 3-5. The fixing tapes shall not protrude beyond the edges of the carrier tape not shall cover the sprocket holes.



Appendix 4

Paper Tape



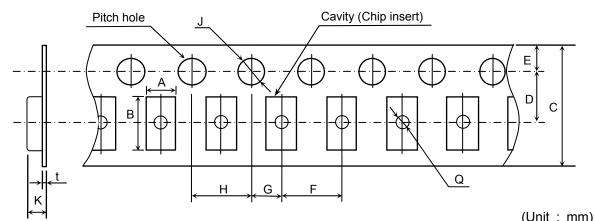
Symbol Type	А	В	С	D	E	F
CKCM25	(1.30)	(1.70)	8.00 ± 0.30	3.50 ± 0.05	1.75 ± 0.10	4.00 ± 0.10
CKCL44	(1.50)	(2.30)	8.00 ± 0.30	3.50 ± 0.05	1.75 ± 0.10	4.00 ± 0.10
Symbol Type	G	Н	J	Т	-	
CKCM25	2.00 ± 0.05	4.00 ± 0.10	Ø 1.5 ^{+0.10}	1.10 max.		
CKCL44	2.00 ± 0.05	4.00 ± 0.10	Ø 1.5 ^{+0.10}	1.10 max.	-	

* The values in the parentheses () are for reference.



Appendix 5

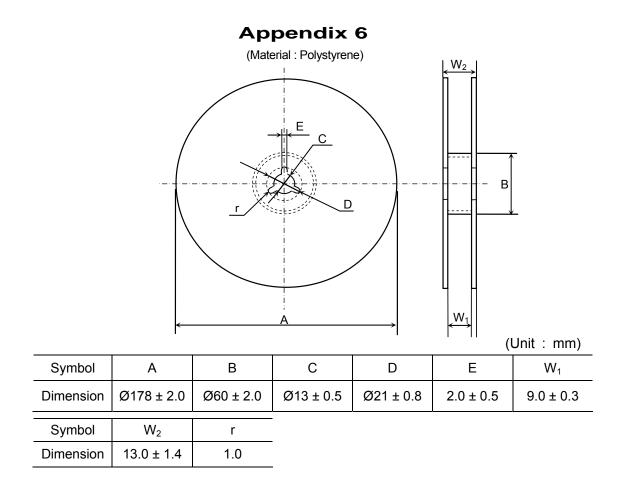
Plastic Tape



· ·						
Symbol Type	А	В	С	D	Е	F
CKCL22	(1.50)	(2.30)	8.00 ± 0.30	3.50 ± 0.05	1.75 ± 0.10	4.00 ± 0.10
CKCA43	(1.90)	(3.50)	8.00 ± 0.30	3.50 ± 0.05	1.75 ± 0.10	4.00 ± 0.10
Symbol Type	G	Н	J	к	t	Q
CKCL22	2.00 ± 0.05	4.00 ± 0.10	Ø 1.5 ^{+0.10}	2.50 max.	0.30 max.	Ø 0.50 min.
CKCA43	2.00 ± 0.05	4.00 ± 0.10	Ø 1.5 ^{+0.10}	2.50 max.	0.30 max.	Ø 0.50 min.

* The values in the parentheses () are for reference.





Appendix 7

(Material : Polystyrene)									
			E C		B B 	(Unit : mm)			
Symbol	А	В	С	D	E	W			
Dimension	Ø382 max. (Nominal Ø330)	Ø50 min.	Ø13 ± 0.5	Ø21 ± 0.8	2.0 ± 0.5	10.0 ± 1.5			
Symbol	t	r							



1.0

Dimension

 2.0 ± 0.5